

Cp E 432: Testing of Computing Systems ELECTRICAL ENGINEERING

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for- manufacture, system testability and diagnosability.

Prerequisites

- El E 351: Models and Circuits I
- El E 385: Advanced Digital Systems
- El E 386: Advanced Digital Systems Laboratory

Instruction Type(s)

• Lecture: Lecture for Cp E 432

Subject Areas

• Computer Engineering, General

Related Areas

Computer Hardware Engineering

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